

Search Notes

Application/Control No.

10/701,716

Examiner

Quynh H. Nguyen

Applicant(s)/Patent under
Reexamination

SMITH, PATRICK

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	220.01 221.01 221.13 219	9/26/2007	QN
370	352 353 354	9/26/2007	QN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched: East, USPGPub, USPAT, EPO, JPO	9/26/2007	QN
Inventor searched in PALM	9/26/2007	QN